



# **CDMMS Annual Business Meeting**

Glen Sanders Mansion-Mohawk Room

Thursday January 13<sup>th</sup>, 2010

5: 30pm-8: 30pm

Cost: \$10 students, \$20 members, \$30 non-members

New membership and/or renewal membership dues will also be collected at this time \$25 for professionals and \$10 for students

## **Agenda**

Cocktail hour at 5:30pm

Dinner will begin at 6pm

Business meeting at 7pm

Talk by Joseph R. Michael, Sandia National Laboratories at 7:30pm

## **Menu**

### **Cocktail Hour**

Fresh Cut Vegetables with Herb Dipping Sauce

- Bread Round with Spinach Dip • Assorted Crackers and Breads

Chaffing dishes of:

Sesame Chicken with Dipping Sauce • Wild Mushroom Puffs

### **Appetizer**

Wild Baby Greens, Grape Tomatoes, Black Olives,  
Julienned Carrots and Sliced Cucumbers with Balsamic Vinaigrette

Entree

New York Strip Steak

12 ounce New York strip, truffle scented mashed potatoes,  
Charred asparagus, wild mushroom au jus

Chicken Breast “Coq Au Vin”

Roasted garlic gravy, roasted carrots accented with sage,  
country smashed potatoes

Imperial Crab Encrusted Tilapia

Israeli couscous, roasted broccolini, lobster sherry cream

*Vegetarian choice available upon request*

### **Dessert**

Celebration Cake with Coffee, Tea and Decaf Service

**PLEASE RSVP WITH YOUR DINNER CHOICE BY  
JANUARY 6<sup>TH</sup>, 2011**



## **Fun with FIB: How FIB can impact many materials characterization techniques**

Joseph R. Michael  
Sandia National Laboratories

Focused ion beam (FIB) tools are becoming more and more common in materials characterization laboratories and have taken a well-deserved position next to SEM and TEM as important tools for materials characterization. In our laboratory, FIB preparation of samples has impacted in a positive way, the traditional areas of TEM and SEM sample preparation but it has also had a big impact in the area of EBSD and other traditional materials characterization technique as well as micromechanical testing. This talk will start out with a brief review of ion/sample interactions. Issues of ion beam modification of the sample and mitigation will be addressed. We will then discuss how FIB sample preparation can impact other materials characterization techniques through the production of unique samples and non-traditional geometries. The use of FIB sequential milling and imaging for obtaining 3D information will be shown.

Sandia National Laboratories is a multi-program laboratory operated by Sandia Corporation, a wholly owned subsidiary of Lockheed Martin Company, for the U.S. Department of Energy's National Nuclear Security Administration under contract DE-AC04-94AL85000.

**\$5 to attend seminar only**



Joe Michael is a Distinguished Member of the Technical Staff at Sandia National Laboratories in Albuquerque, NM, where he develops and applies electron and ion microscopy to the characterization of materials in the Materials Characterization Department of the Materials Science Center. Joe has received numerous awards and honors from MAS, MSA, and other societies. He is a co-author of the leading textbook on Scanning Electron Microscopy, has authored many book chapters, and has published over 100 papers in microscopy and microanalysis. He received his BS, MS and PhD. in Materials Science and Engineering from Lehigh University in Bethlehem, Pa.